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标题: Waveguide artefacts in terahertz near field imaging

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摘要: We report experimental and computational studies of the behaviour of a photoconductive THz near field probe when imaging a simple planar metal-dielectric structure. We show that the excitation of waveguide modes in the gap between sample and probe, together with diffraction at the probe, must generally be taken into account when analysing images and that electromagnetic simulations provide a very useful aid to interpretation. (C) 2012 American Institute of Physics. [http://dx.doi.org/10.1063/1.4714532]

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